

AP95T10AGI-HF-VB Datasheet N-Channel 100 V (D-S) 175 °C MOSFET

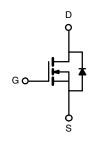
PRODUCT SUMMARY	
V _{DS} (V)	100
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0.0038
I _D (A)	120
Configuration	Single

FEATURES

- TrenchFET[®] Power MOSFET
- Package with Low Thermal Resistance
- 100 % $\rm R_g$ and UIS Tested







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	$(T_C = 25 \degree C, unles)$	s otherwise noted)	
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	100	v
Gate-Source Voltage		V _{GS}	± 20	
Continuous Drain Current	T _C = 25 °C ^a	1	120	
Continuous Drain Current	T _C = 125 °C	- I _D	102	
Continuous Source Current (Diode Conduction) ^a		I _S	120	А
Pulsed Drain Current ^b		I _{DM}	480	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	73	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	266	mJ
Maximum Dawar Disaination ^b	T _C = 25 °C	P	84	W
Maximum Power Dissipation ^b	T _C = 125 °C	- P _D	35	VV
Operating Junction and Storage Temperature	Range	T _J , T _{stg}	- 55 to + 175	°C

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	40	°C/W
Junction-to-Case (Drain)		R _{thJC}	0.6	0/2

Notes

a. Package limited.

b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static	1				<u> </u>			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0, I_D = 250 \ \mu A$		100	-	-		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.5	3.0	3.5	v	
Gate-Source Leakage	I _{GSS}	V _{DS} =	0 V, V _{GS} = ± 20 V	-	-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = 100 V	-	-	1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 125 °C	-	-	50	μA	
		$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 175 °C	-	-	500	V nA μA Λ Ω S pF nC Ω ns	-
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	120	-	-	Α	
		V _{GS} = 10 V	I _D = 20 A	-	0.0038	-	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A, T _J = 125 °C	-	0.0064	-		
		V _{GS} = 10 V	I _D = 20 A, T _J = 175 °C	-	0.0080	-		
Forward Transconductanceb	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		-	82	-	S	
Dynamic ^b	-							
Input Capacitance	C _{iss}			-	5780	7230		
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 25 V, f = 1 MHz	-	3070	3840	pF	
Reverse Transfer Capacitance	C _{rss}	1		-	305	385		
Total Gate Charge ^c	Qg			-	125	190		
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 50 \text{ V}, I_D = 70 \text{ A}$	-	28	-	nC	
Gate-Drain Charge ^c	Q _{gd}	1		-	46	-		
Gate Resistance	Rg	f = 1 MHz		1.6	3.3	5	Ω	
Turn-On Delay Time ^c	t _{d(on)}			-	16	25		
Rise Time ^c	t _r	$\begin{array}{l} V_{\text{DD}}=\text{50 V, R}_{\text{L}}=\text{0.7 }\Omega\\ I_{\text{D}}\cong\text{70 A, V}_{\text{GEN}}=\text{10 V, R}_{\text{g}}=\text{1 }\Omega \end{array}$		-	110	165	ns	
Turn-Off Delay Time ^c	t _{d(off)}			-	40	60		
Fall Time ^c	t _f	1		-	12	20	1	
Source-Drain Diode Ratings and Chara	acteristics ^b							
Pulsed Current ^a	I _{SM}			-	-	480	Α	
Forward Voltage	V _{SD}	I _F =	= 100 A, V _{GS} = 0	-	0.9	1.5	V	

Notes

a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

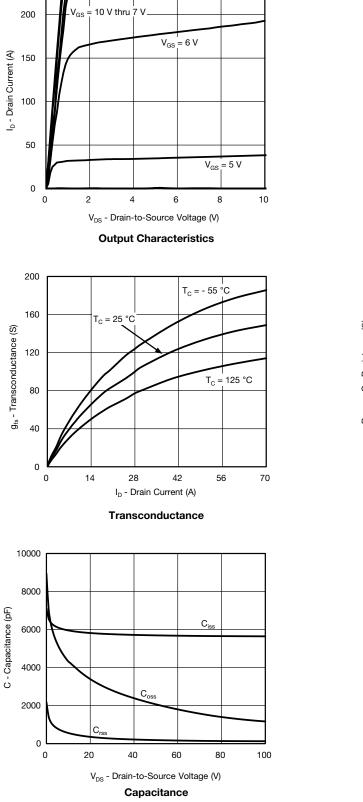
c. Independent of operating temperature.

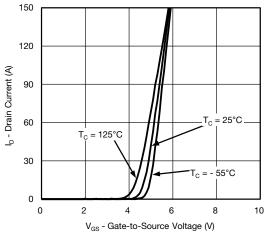
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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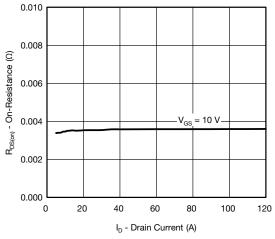


TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)

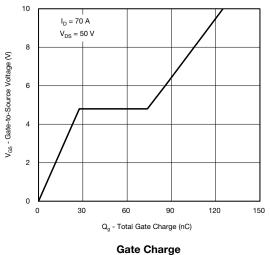




Transfer Characteristics

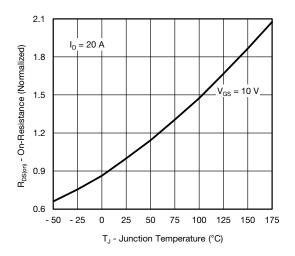


On-Resistance vs. Drain Current

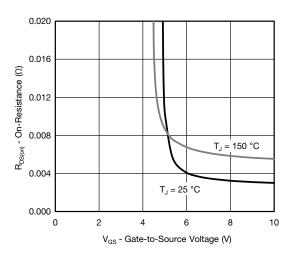




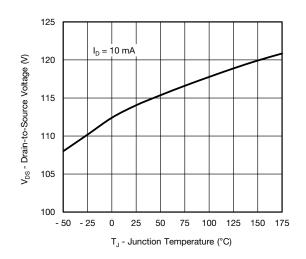
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



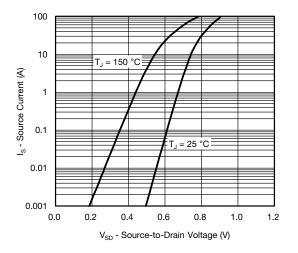
On-Resistance vs. Junction Temperature



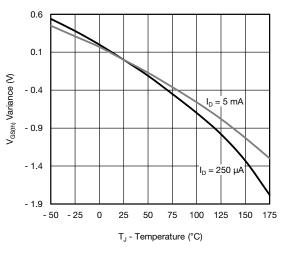
On-Resistance vs. Gate-to-Source Voltage



Drain Source Breakdown vs. Junction Temperature



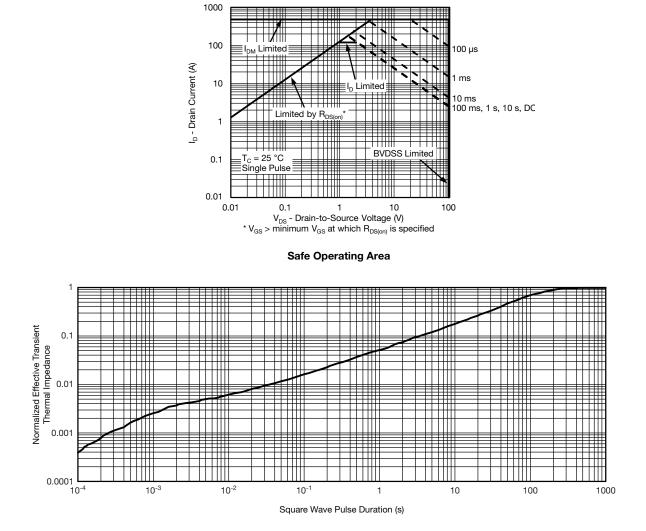
Source Drain Diode Forward Voltage



Threshold Voltage



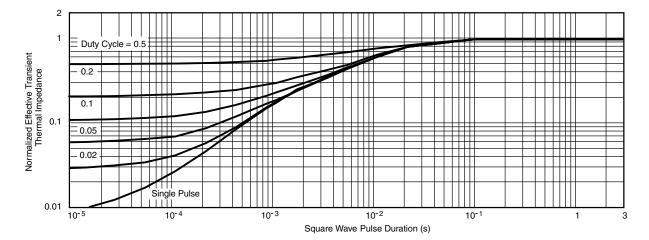
THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

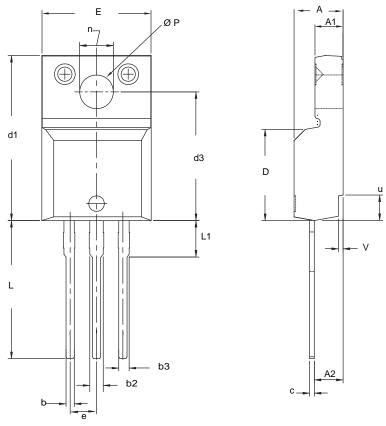
Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLI	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØP	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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